

U.S. National Stage of PCT/EP2003/013839

**Amendments to the Abstract:**

**ABSTRACT**

Please replace the abstract that appears on page 9 of the specification with the following revised abstract which is submitted on a separate sheet.

Abstract

An ion-sensitive sensor arrangement includes: A semiconductor chip [[1]] having a first surface, which has a media-sensitive region [[4]] and at least one, first, electrical contact surface [[2, 3]]; and a support [[6]] having a second surface, which faces the first surface of the semiconductor, has an opening [[7]], which aligns with the sensitive region [[4]], and at least one, second, electrical contact surface [[8, 9]], which overlaps, or aligns with, the at least one, first, electrical contact surface; wherein, between the support and the semiconductor chip, a preferably elastic, anisotropic conductor [[5]] is arranged, which produces a conducting connection between the at least one, first, contact surface and the at least one, second, contact surface, and which has a traversing opening, which aligns with the opening [[7]] in the second surface, so that the sensitive region [[4]] of the semiconductor chip [[1]] can be contacted through the opening by an analyte, wherein the preferably elastic, anisotropic conductor [[5]] seals the region outside of the opening [[7]] against contamination with the analyte.

[[Fig. 3]]